

Resistive AC-Coupling: a new readout paradigm in 4D tracking with Ultra-Fast Silicon Detectors

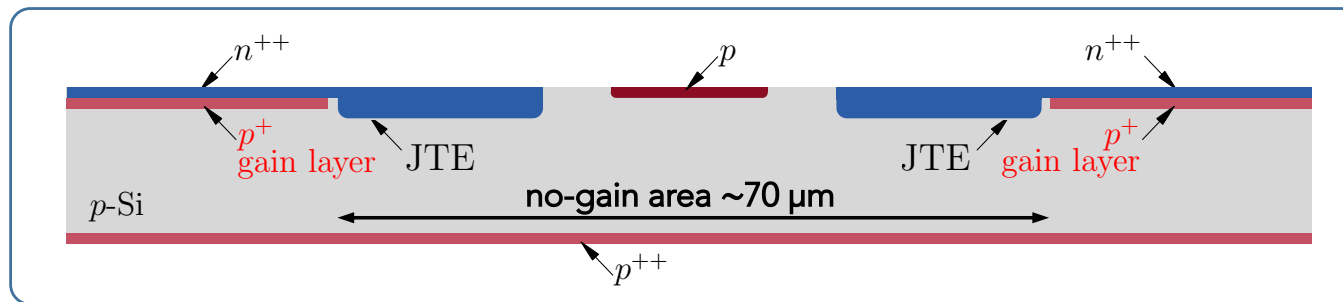
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13th "Trento" Workshop – Munich, 19-21 February 2018

Motivations

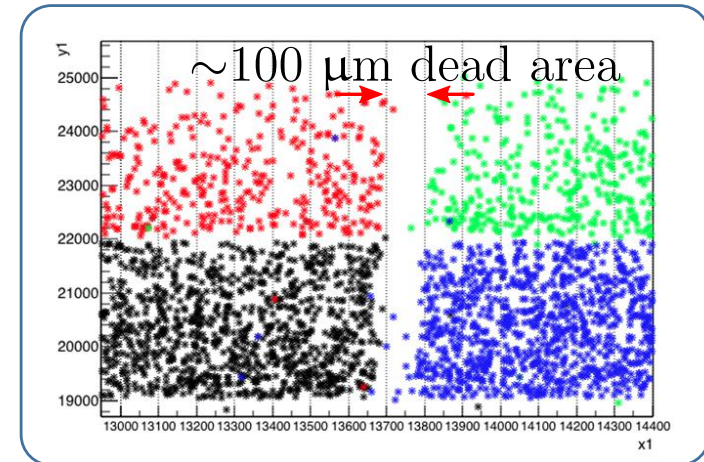
- In the current **UFSD** design, **isolation structures** between readout pads represent a **no-gain area** for the signal collection



present limit
of no-gain area
in the UFSD design
 $70\text{-}100 \mu\text{m}$

- **Beam-test** results confirm the presence of a non-gain space between active regions:
 - HPK: $100 \mu\text{m}$
 - FBK: $70 \mu\text{m}$
 - CNM: $70 \mu\text{m}$

pre-print on 2017 test-beam @ FNAL (H. Sadrozinski et al.)



Motivations

- TCAD simulations performed on 50- μm UFSD show that, even with the **most aggressive design rules**, a **no-gain area of about 40 μm** is produced

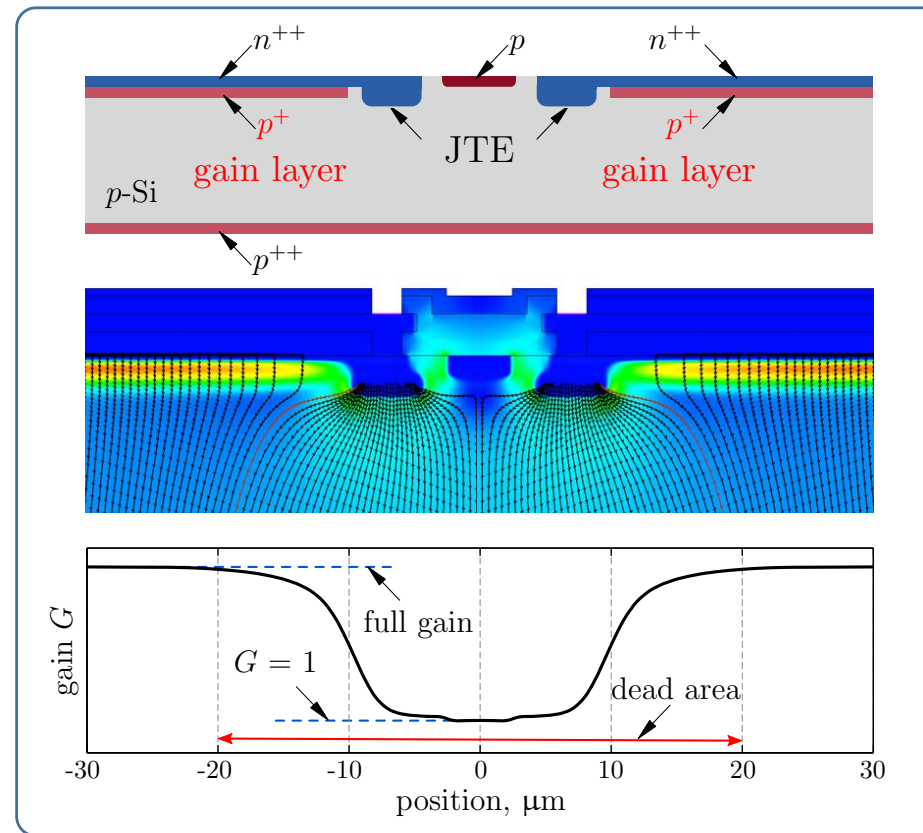
device sketch



field simulation



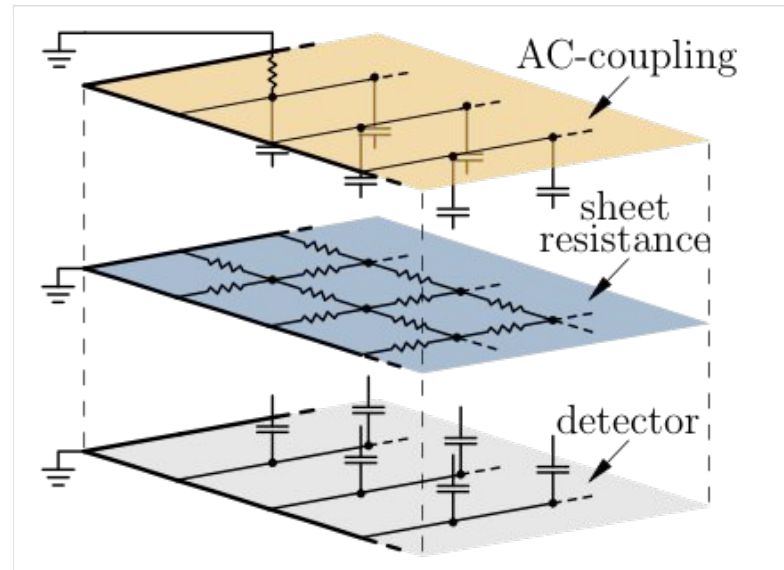
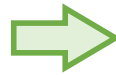
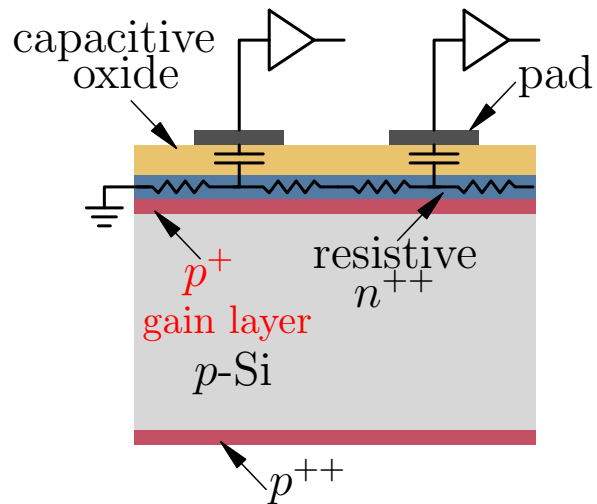
gain simulation



physical limit
30-40 μm

The RSD paradigm

Resistive AC-Coupled Silicon Detectors – RSD



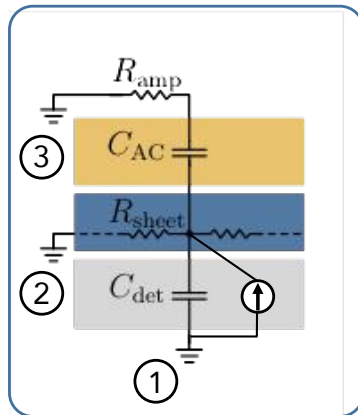
device-level sketch

circuit model

The RSD paradigm

Design Goals:

- Realize a readout with the **lowest impedance path**
- The **readout characteristic time** is short enough for the signal to be seen, and long enough to minimize pile-up



1) Detector bulk:

Small detector capacitance C_{det} (units of pF) then

⇒ **High signal impedance**

2) Resistive layer:

Resistivity in the n^{++} layer will be accurately chosen

⇒ Example 1: $R_{\text{sheet}} = 1 \text{ k}\Omega$ (i.e. discharging time $t \sim 100 \text{ ns}$)

⇒ Example 2: $R_{\text{sheet}} = 60 \Omega$ in AC-LGAD by CNM

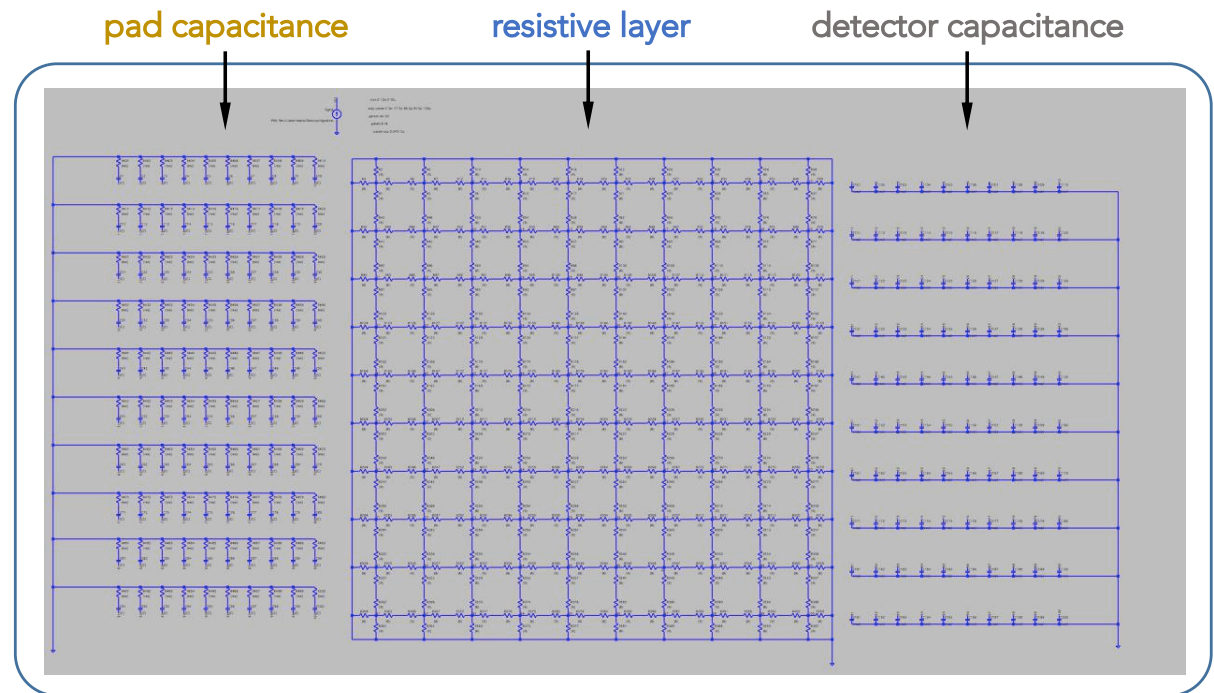
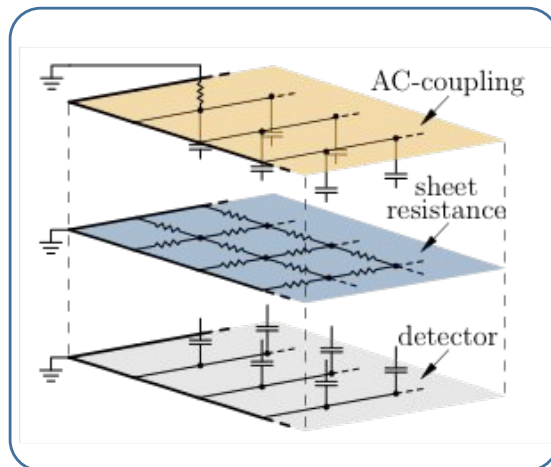
3) AC coupling + amplifier input impedance:

Since we expect $C_{\text{AC}} \sim 100 \text{ pF}$ then

⇒ **Low signal impedance**

RSD preliminary simulations

The **equivalent circuit** is modeled with **Spice**



How large should the AC pad be so that the signal is similar to the input current, still having a large coupling capacitance?

RSD preliminary simulations

Cross-talk between pads

Simulation parameters:

Pad size: $500 \times 500 \mu\text{m}^2$

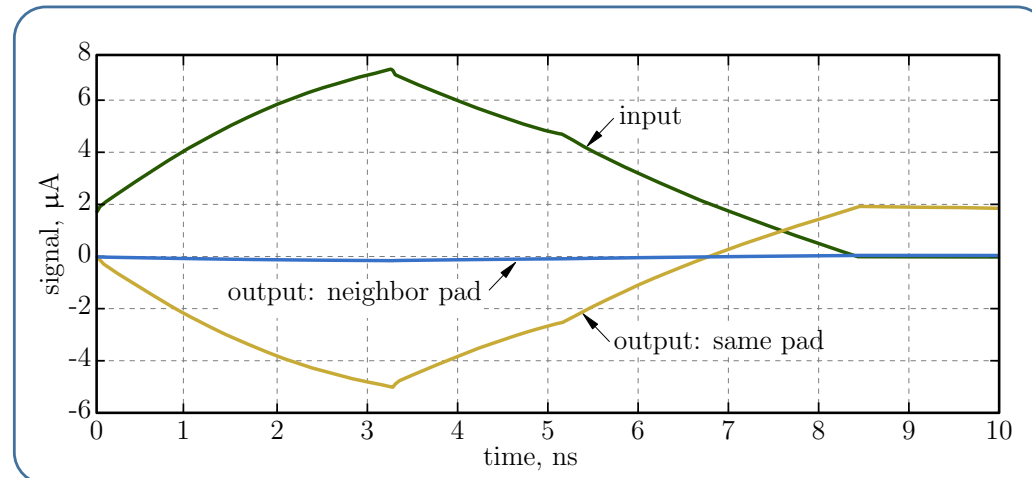
Oxide/passivation thickness: 250 nm

Pad capacitance: $C_{AC} = 48.5 \text{ pF}$

Sheet resistance: $R_{\text{sheet}} = 1 \text{ k}\Omega$

Detector capacitance: $C_{\text{det}} = 0.3 \text{ pF}$

Output resistance: $R_{\text{amp}} = 50 \Omega$



simulations performed by M. Ferrero

- By choosing the optimal circuital parameters, **each read-out pad is almost insensitive to next-neighbor nodes**
- Thanks to the **high sheet resistance R_{sheet}** , the pre-amp stage sees only a **small volume** of the detector, so that the noise due to leakage contribution is similar of that of standard UFSD

RSD preliminary simulations

Sheet resistance homogeneity

Simulation parameters:

Pad size: $500 \times 500 \mu\text{m}^2$

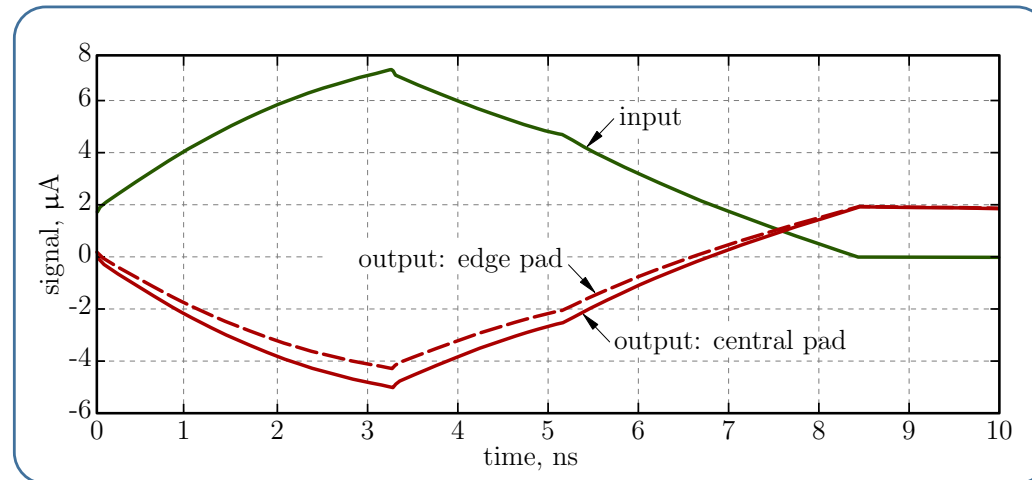
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Detector capacitance: $C_{\text{det}} = 0.3 \text{ pF}$

Output resistance: $R_{\text{amp}} = 50 \Omega$



simulations performed by M. Ferrero

- The **difference** in terms of **signal peak** is about **0.4 μA**

RSD preliminary simulations

Pad size

Simulation parameters:

Pad size: **300 - 500 - 900 μm**

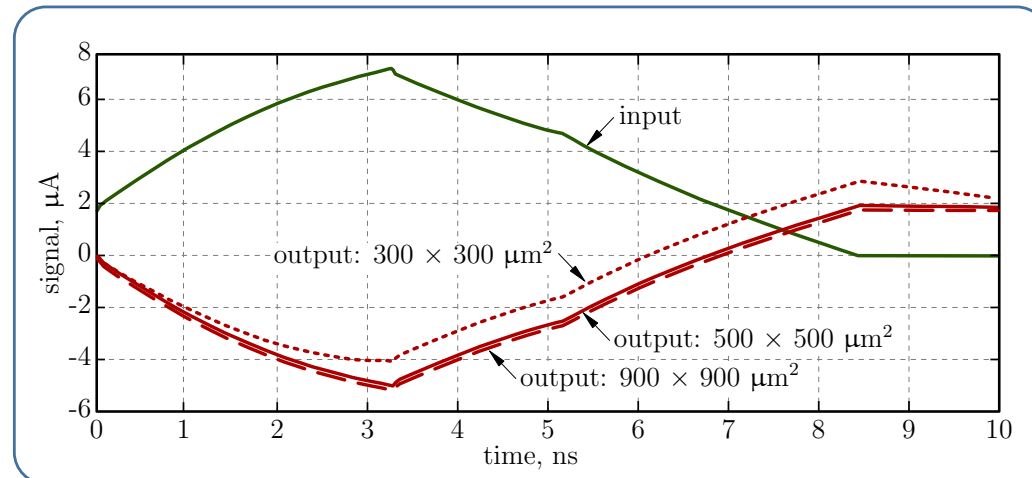
Oxide/passivation thickness: **250 nm**

Pad capacitance: $C_{AC} = 48.5 \text{ pF}$

Sheet resistance: $R_{\text{sheet}} = 1 \text{ k}\Omega$

Detector capacitance: $C_{\text{det}} = 0.3 \text{ pF}$

Output resistance: $R_{\text{amp}} = 50 \Omega$



simulations performed by M. Ferrero

- The output signal is larger when pad area increases

RSD preliminary simulations

n^{++} resistivity

Simulation parameters:

Pad size: $500 \times 500 \mu\text{m}^2$

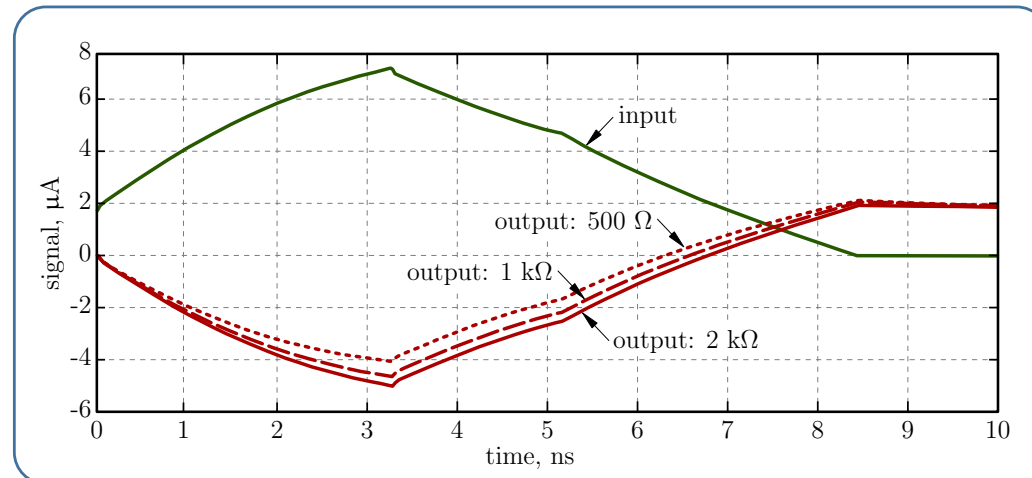
Oxide/passivation thickness: 250 nm

Pad capacitance: $C_{AC} = 48.5 \text{ pF}$

Sheet resistance: $R_{\text{sheet}} = 0.5 - 1 - 2 \text{ k}\Omega$

Detector capacitance: $C_{\text{det}} = 0.3 \text{ pF}$

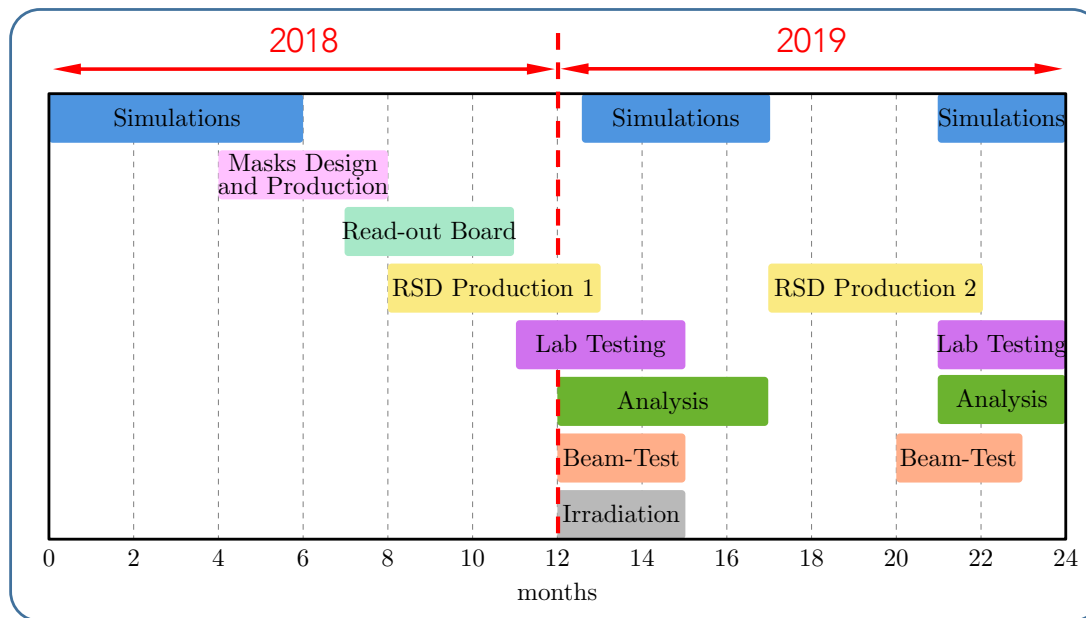
Output resistance: $R_{\text{amp}} = 50 \Omega$



simulations performed by M. Ferrero

- In UFSD the n^{++} layer is generally doped by As with $N_{\text{peak}} \sim 10^{19} \text{ cm}^{-3}$ and depth approximately 1 μm . Sheet resistance between 0.1 Ω and some units of $\text{k}\Omega$ can be achieved while maintaining a doping high enough to obtain a working UFSD

The project planning



► **Involved Institutes:** INFN-Torino & FBK

► **Working packages:**

WP1: Spice and TCAD simulations

WP2: design and production of lithographic masks

WP3: RSD productions

WP4: readout board production and laboratory testing of sensors

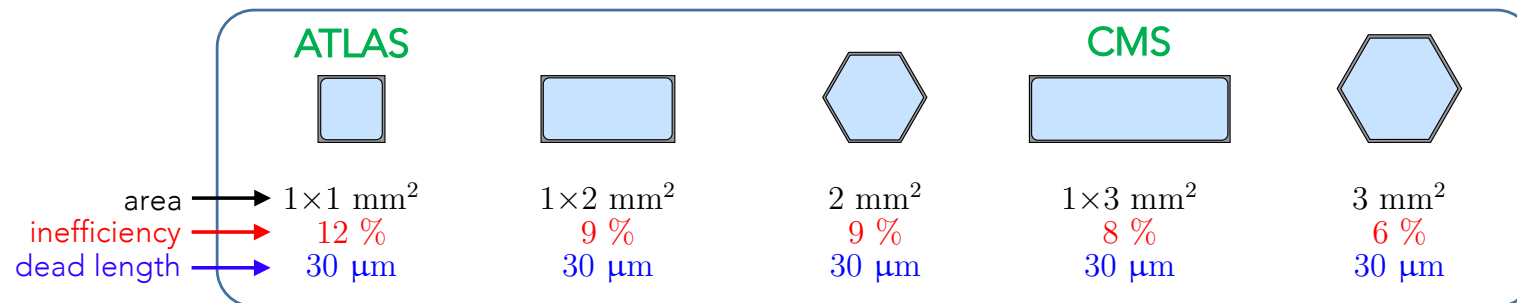
WP5: beam tests at CERN North Area

WP6: irradiation

► **Total cost:** ~100 k€ (funded by INFN)

Conclusions

- The **RSD project** – already approved by INFN – wants to circumvent the issues related to low fill-factors, by completely **eliminating the no-gain** area between adjacent pads
- The most important **application fields of RSD devices** could be the **high-rate, radiation-intense** and **high-pile-up environments** (high-energy physics), but also in other areas of applied physics as in **therapeutic beam monitoring**, where the UFSD technology is currently under consideration (see Anna Vignati's talk)



- **Collaboration** with other research groups working on **AC-LGADs** is highly welcome!

see you in **next Trento Workshop** with **updates about the RSD project!**

Acknowledgments

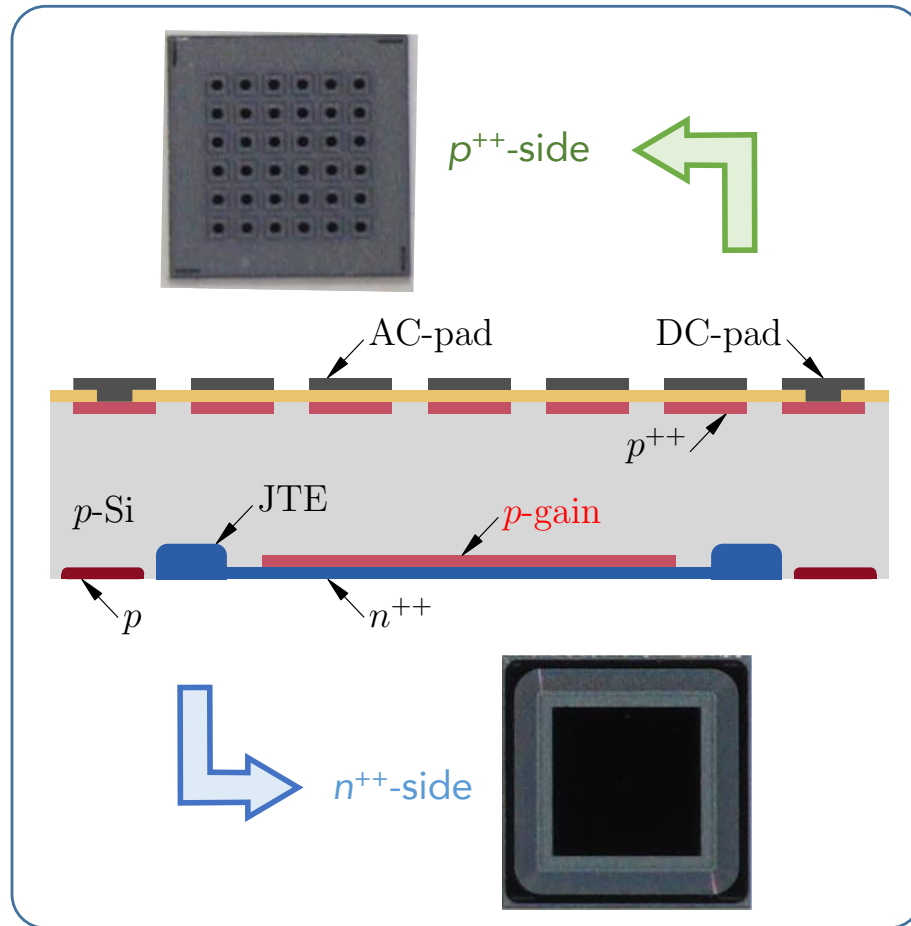
RSD is a project supported by the “Gruppo 5” of the Italian National Institute for Nuclear Physics (INFN)

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Thank you for your attention!

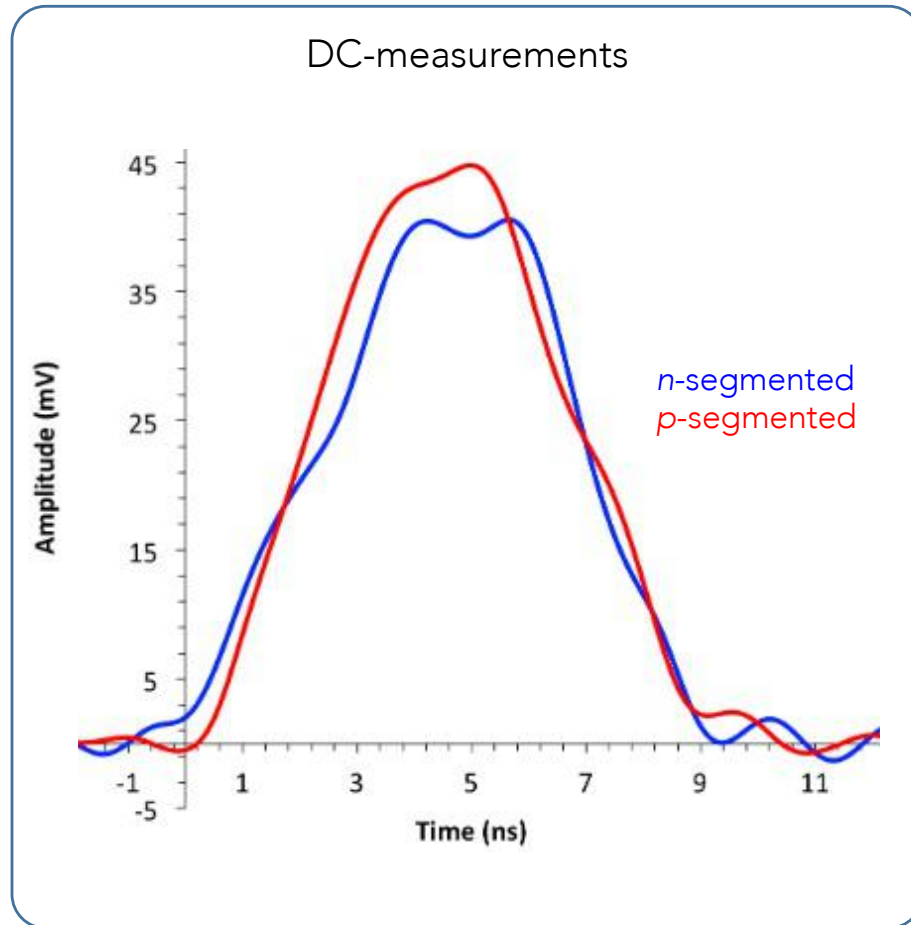
Backup

p-segmented UFSD1



Besides *n*-segmentation, the first UFSD production at FBK (300 μm) also accounted for ***p*-side segmentation**.

p-segmented UFSD1



Besides *n*-segmentation, the first UFSD production at FBK (300 μm) also accounted for ***p*-side segmentation**.

- No relevant differences between the two signals (pad size \gg thickness)
- *n*- and *p*-segmented sensors have the **same weighting field**
- *n*- and *p*-segmented signals have the **same width** (~ 9 ns);